INFORMATION DISCLOSURE CITATION PTO-1449				Atty Docket: 061450/0304607 FID-101-D3 Applicant: S. Prakash		Serial No. to be assigned		
Submitted: July 3, 2003				Filing Date: Herewith		Prior Group Art Unit: 2856		
		U.S.	PATENT	APPLICATIONS	· · · · · · · · · · · · · · · · · · ·			
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME		CLASS	SUBCLASS	FILING DATE	
RE	5,723,981	03 Mar 1998	Hellemans et al.		324	719	06/25/	9 6
/	5,992,226	11/1999	Green et al.		73	105		
	5,763,768	06/1998	Henderson, et al.		. 73	105		
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		FORE	IGN PAT	ENT DOCUMENTS	•	• • • • • • • • • • • • • • • • • • • •		*
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY		CLASS	SUBCLASS	Translation Yes No	
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	OTHER DOC	UMENTS (Incl	uding Au	ithor, Title, Date, Pe	rtinent Page	s, Etc.)	- V	<u> </u>
De Wolf, et al. "Lateral and vertical dopant profiling in semiconductors by atomic force microscopy using conducting tops" (J. Vac. Sci. Tech. A 13(3), May/June 1995, pp. 1699-1704								
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EXAMINER	RAEVIJ			DATE CONSIDERED	/2-2	9-03		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance <u>and</u> not considered. Include copy of this form with next communication to applicant.